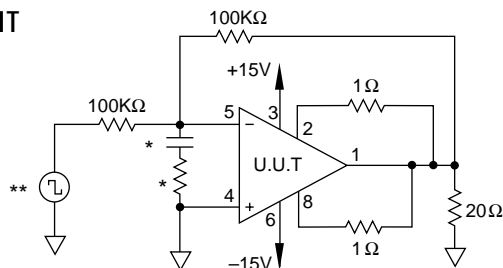


# PA12M

SG	PARAMETER	SYMBOL	TEMP.	POWER	TEST CONDITIONS	MIN	MAX	UNITS
1	Quiescent current	$I_Q$	25°C	±40V	$V_{IN} = 0, A_V = 100, R_{CL} = .1\Omega$		50	mA
1	Input offset voltage	$V_{OS}$	25°C	±40V	$V_{IN} = 0, A_V = 100$		±6	mV
1	Input offset voltage	$V_{OS}$	25°C	±10V	$V_{IN} = 0, A_V = 100$		±12	mV
1	Input offset voltage	$V_{OS}$	25°C	±45V	$V_{IN} = 0, A_V = 100$		±7	mV
1	Input bias current, +IN	$+I_B$	25°C	±40V	$V_{IN} = 0$		±30	nA
1	Input bias current, -IN	$-I_B$	25°C	±40V	$V_{IN} = 0$		±30	nA
1	Input offset current	$I_{OS}$	25°C	±40V	$V_{IN} = 0$		±30	nA
3	Quiescent current	$I_Q$	-55°C	±40V	$V_{IN} = 0, A_V = 100, R_{CL} = .1\Omega$		100	mA
3	Input offset voltage	$V_{OS}$	-55°C	±40V	$V_{IN} = 0, A_V = 100$		±11.2	mV
3	Input offset voltage	$V_{OS}$	-55°C	±10V	$V_{IN} = 0, A_V = 100$		±17.2	mV
3	Input offset voltage	$V_{OS}$	-55°C	±45V	$V_{IN} = 0, A_V = 100$		±12.2	mV
3	Input bias current, +IN	$+I_B$	-55°C	±40V	$V_{IN} = 0$		±115	nA
3	Input bias current, -IN	$-I_B$	-55°C	±40V	$V_{IN} = 0$		±115	nA
3	Input offset current	$I_{OS}$	-55°C	±40V	$V_{IN} = 0$		±115	nA
2	Quiescent current	$I_Q$	125°C	±40V	$V_{IN} = 0, A_V = 100, R_{CL} = .1\Omega$		50	mA
2	Input offset voltage	$V_{OS}$	125°C	±40V	$V_{IN} = 0, A_V = 100$		±12.5	mV
2	Input offset voltage	$V_{OS}$	125°C	±10V	$V_{IN} = 0, A_V = 100$		±18.5	mV
2	Input offset voltage	$V_{OS}$	125°C	±45V	$V_{IN} = 0, A_V = 100$		±13.5	mV
2	Input bias current, +IN	$+I_B$	125°C	±40V	$V_{IN} = 0$		±70	nA
2	Input bias current, -IN	$-I_B$	125°C	±40V	$V_{IN} = 0$		±70	nA
2	Input offset current	$I_{OS}$	125°C	±40V	$V_{IN} = 0$		±70	nA
4	Output voltage, $I_o = 10A$	$V_o$	25°C	±16V	$R_L = 1\Omega$	10		V
4	Output voltage, $I_o = 80mA$	$V_o$	25°C	±45V	$R_L = 500\Omega$	40		V
4	Output voltage, $I_o = 5A$	$V_o$	25°C	±35V	$R_L = 6\Omega$	30		V
4	Current limits	$I_{CL}$	25°C	±14V	$R_L = 6\Omega, R_{CL} = 1\Omega$	.6	.89	A
4	Stability/noise	$E_N$	25°C	±40V	$R_L = 500\Omega, A_V = 1, C_L = 1.5nF$		1	mV
4	Slew rate	SR	25°C	±40V	$R_L = 500\Omega$	2.5	10	V/ $\mu$ s
4	Open loop gain	$A_{OL}$	25°C	±40V	$R_L = 500\Omega, F = 10Hz$	96		dB
4	Common mode rejection	CMR	25°C	±15V	$R_L = 500\Omega, F = DC, V_{CM} = \pm 9V$	74		dB
6	Output voltage, $I_o = 8A$	$V_o$	-55°C	±14V	$R_L = 1\Omega$	8		V
6	Output voltage, $I_o = 80mA$	$V_o$	-55°C	±45V	$R_L = 500\Omega$	40		V
6	Stability/noise	$E_N$	-55°C	±40V	$R_L = 500\Omega, A_V = 1, C_L = 1.5nF$		1	mV
6	Slew rate	SR	-55°C	±40V	$R_L = 500\Omega$	2.5	10	V/ $\mu$ s
6	Open loop gain	$A_{OL}$	-55°C	±40V	$R_L = 500\Omega, F = 10Hz$	96		dB
6	Common mode rejection	CMR	-55°C	±15V	$R_L = 500\Omega, F = DC, V_{CM} = \pm 9V$	74		dB
5	Output voltage, $I_o = 8A$	$V_o$	125°C	±14V	$R_L = 1\Omega$	8		V
5	Output voltage, $I_o = 80mA$	$V_o$	125°C	±45V	$R_L = 500\Omega$	40		V
5	Stability/noise	$E_N$	125°C	±40V	$R_L = 500\Omega, A_V = 1, C_L = 1.5nF$		1	mV
5	Slew rate	SR	125°C	±40V	$R_L = 500\Omega$	2.5	10	V/ $\mu$ s
5	Open loop gain	$A_{OL}$	125°C	±40V	$R_L = 500\Omega, F = 10Hz$	96		dB
5	Common mode rejection	CMR	125°C	±15V	$R_L = 500\Omega, F = DC, V_{CM} = \pm 9V$	74		dB

## BURN IN CIRCUIT



\* These components are used to stabilize device due to poor high frequency characteristics of burn in board.

\*\* Input signals are calculated to result in internal power dissipation of approximately 2.1W at case temperature = 125°C.